

Parameter	PA Module	Conventional UT	
Configuration	Receiver/Pulser	32/64PR, 16/64PR	1/1
	Range	9900μs	9900μs
	Velocity	340-15240m/s	340-15240m/s
Pulser	Test Mode	PE/PC	PE/PC/TT/TOFD
	Voltage	10V-100V, 1V Step	100V/200V/400V
	Pulse Shape	Negative Square Wave	Negative Square Wave
	Pulse Width	25-1000ns/2.5ns	30-1000ns/2.5ns
	Rise Time	<4ns	<8ns
	PRF	20KHz	10KHz
	Delay	20μs/2.5ns	20μs/2.5ns
	Damp	NA	200Ω
Receiver	Gain	0-120dB	0-120dB
	Bandwidth	0.5-20MHz	0.5-20MHz
	Delay	20μs/2.5ns	20μs/2.5μs
Data Acquisition	Sampling Rate	100MHz	100MHz
	ADC	16bit	14bit
	Maximum Amplitude	800%	800%
	Max Length of A scan	16384	16384
	Number of focusing rules	1024	NA
	Focus Type	True Depth/Sound Path/Projection/Focal Plane	NA
	Detection	FW/HW+/HW-/RF	FW/HW+/HW-/RF
	Synchronize	Initial Pulse or Gate	Initial Pulse or Gate
Scan/Display	Detection Mode	PA/UT/TOFD/FMC-TFM/PWI-TFM	
	Type	TFM/Linear/Sectorial/Compound scanning	NA
	Display Mode	A/B/S/C/TFM/3D/TopC/Strip Chart	A/B/C/Strip Chart
Adaptive Filtering		Yes	NA
Band Filter		Full Time Data Averaging	NA
TCG	Point	16	16
	Gain Range	40dB	40dB
	Max Gain Slope	40dB/10ns	40dB/μs
Gate	Number	A/B/C/I+Custom Gate	
	Threshold	0-100%	
	Gate Trigger Mode	Peak/Leading Edge	
Report		WORD, PDF, EXCEL	
Display Screen	Size	10.1 inch	
	Resolution	1920*1200 pixel	
	Type	Industrial TFT LCD Touch Screen	
	USB 3.0	2个USB3.0	
I/O Port	Ethernet	1个, 1000 Mb/s	
	Video Output	HDMI1.4b	
	Encoder	RL 16-pin	
Language		Chinese/English/Russian/French/German/Italian	
Power Supply	DC Supply Voltage	15V DC	
	Battery Type	Lithium battery 10.8V 97.2Wh	
	Continuous Working Time	About 4 hours (1 battery)	
Case	Size	302mm*230mm*84mm	
	Weight	2.7kg (without battery) 3.2kg (with 1 battery)	

Stock code: 301528

PAUT DETECTOR NOVASCAN L3



NOVASCAN L3

Phased array ultrasonic detector

NOVASCAN L3 is a portable phased array ultrasonic detector integrating PA / UT / TFM / TOFD. It is aimed at field detection and engineering application scenarios. While ensuring high detection performance, it achieves lightweight and highly integrated design, making it suitable for non-destructive testing needs in multiple industries and working conditions.

Lightweight design

- Only 2.7 kg, significantly reducing the burden of field operations
- Suitable for complex environments such as working at height, in small spaces, and outdoor inspections
- Easier to carry and operate for a long time, improving detection efficiency

Cost-effective choice

- Full-function configuration without redundancy
- Gain more comprehensive and professional testing capabilities at a more reasonable cost
- Especially suitable for industrial users such as testing agencies and engineering construction teams

High-performance configuration accurate and efficient

- PRF up to 20 KHz, high-speed scanning, online efficiency
- 0.5–20 MHz wide frequency band, compatible with a variety of common probes, reducing usage costs
- 800% A-scan display height, small defects are clearly presented, effectively reducing the risk of missed detection and misjudgment

All-round mode one machine is multi-purpose

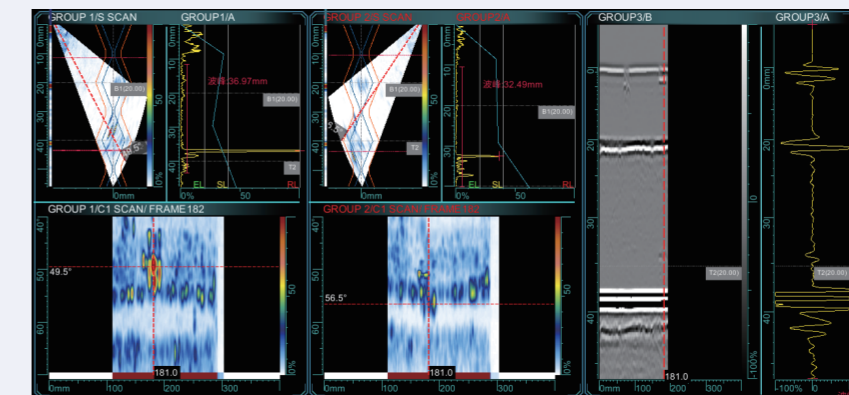
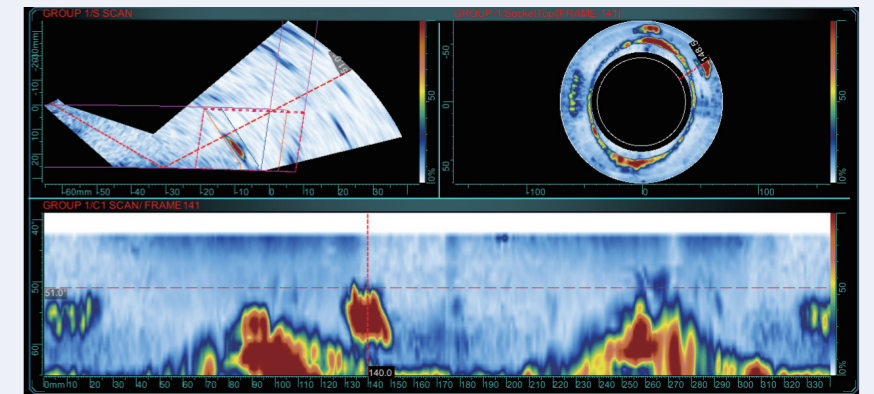
- Integrated four core detection modes: PA / UT / TFM / TOFD
- Cover applications such as weld inspection, thickness measurement, material flaw detection, etc
- Meet diverse inspection needs from routine inspections to large-scale projects

Typical application

Petrochemical/electric energy/rail transit/aerospace/steel structure and pressure vessel inspection

Dedicated imaging algorithm support

The software has a built-in Doppler combined with Doppler's nozzle weld imaging algorithm, it delivers clear weld geometry and precise defect visualization, which is used in conjunction with the MOS 07 nozzle weld scanner to achieve stable acquisition of weld data and multi-view imaging, and the defect displays clear and intuitive.



Integration of multiple detection modes

Integrate multiple detection modes such as PA, UT, TFM, and TOFD to meet the needs of most industrial non-destructive testing application scenarios.

Total Focus Imaging (TFM) comprehensive coverage of algorithms

Supports a variety of TFM imaging paths and algorithm combinations to meet the high-resolution detection needs of different materials, structures and defect types.

